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Fabrication and characterization of TiO₂/SiO₂ based Bragg reflectors for light trapping applications

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Highlights

- Fabrication of Bragg reflectors via simple and cost-effective method is presented.
- Seven-DBR stacks of TiO₂/SiO₂ showed maximum reflectance 90% at wavelength 617 nm.
- FESEM image confirmed the alternate layers of TiO₂ and SiO₂ films in onedirection.
- The proposed solar cell design with 7DBR stacks improved the light absorption.

Abstract

Distributed Bragg reflectors (DBRs) have received an intensive attention due to their increasing demand in optoelectronic and photonic devices. Such reflectors are capable to prohibit the light propagation within the specified wavelength range of interest. In this paper, we present the